INTERNATIONAL STANDARD

Geometrical Product Specifications (GPS) — Surface texture: Profile method — Terms, definitions and surface texture parameters

AMENDMENT 1: Peak count number

Spécification géométrique des produits (GPS) — État de surface: Méthode du profil — Termes, définitions et paramètres d'état de surface

AMENDEMENT 1: Nombre de pics

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ISO 4287:1997/Amd 1:2009
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Foreword

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International Standards are drafted in accordance with the rules given in the ISO/IEC Directives, Part 2.

The main task of technical committees is to prepare International Standards. Draft International Standards adopted by the technical committees are circulated to the member bodies for voting. Publication as an International Standard requires approval by at least 75 % of the member bodies casting a vote.

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Amendment 1 to ISO 4287:1997 was prepared by Technical Committee ISO/TC 213, *Dimensional and geometrical product specifications and verification*.

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AMENDMENT 1: Peak count number

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Add the following entry.

4.3.2
peak count number
PPc, RPc, WPc
number of mean widths of the profile elements (PSm, RSm, WSm) in a reference length (L)

$$PPc = \frac{L}{PSm}; \quad RPc = \frac{L}{RSm}; \quad WPc = \frac{L}{WSm}$$

NOTE 1   A reference length of 10 mm is recommended, if not otherwise specified.

NOTE 2   When calculating the peak count number, a height discrimination threshold of RSm being ± 0,5 µm is recommended.

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Price based on 1 page